Notice of References Cited

Application/Control No. 10/685,352	Applicant(s)/Pater Reexamination VALLEY ET AL.	nt Under
Examiner	Art Unit	
SAIF A. ALHIJA	2128	Page 1 of 1

U.S. PATENT DOCUMENTS

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	Α	US-			
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NON-PATENT DOCUMENTS

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*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
*	U	Ruehli et al. "Progress in the Methodologies for the Electrical Modeling of Interconnects and Electronic Packages.", IEEE May 2001.			
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A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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